PC8141xNSZ **Series**

DIP 4pin High CMR, **AC Input, Low Input Current Photocoupler**



Description

PC8141xNSZ Series contains an IRED optically coupled to a phototransistor.

It is packaged in a 4-pin DIP, available in SMT gullwing lead-form option.

Input-output isolation voltage(rms) is 5.0kV.

Collector-emitter voltage is 80V^{(*),} CTR is 50% to 600% at input current of ±0.5mA and CMR is MIN. 10kV/µs.

Features

- 1. 4-pin DIP package
- 2. Double transfer mold package (Ideal for Flow Soldering)
- 3. AC input type
- 4. Low input current type (I_F=±0.5mA)
- 5. High collector-emitter voltage (V_{CEO} : 80V^(*))
- 6. High noise immunity due to high common rejection voltage (CMR : MIN. 10kV/µs)
- 7. High isolation voltage between input and output $(V_{iso(rms)} : 5.0 \text{ kV})$

(*)Up to Date code "P8"(August 2002)VCEO:70V.

Agency approvals/Compliance

- 1. Recognized by UL1577 (Double protection isolation), file No. E64380 (as model No. PC8141)
- 2. Package resin : UL flammability grade (94V-0)

Applications

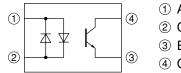
- 1. Programmable controllers
- 2. Facsimiles
- 3. Telephones

Notice The content of data sheet is subject to change without prior notice

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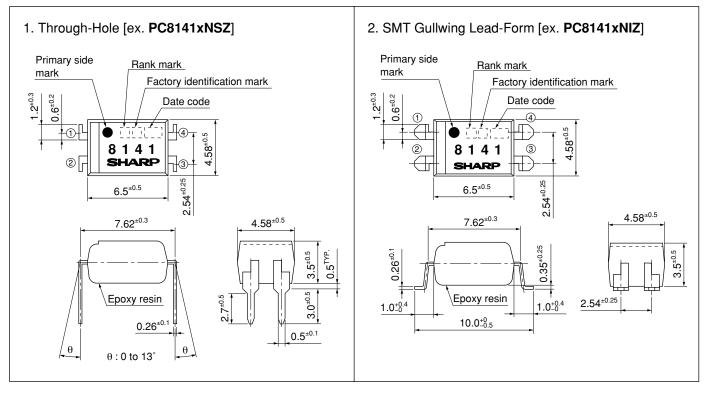
Internal Connection Diagram



Anode/Cathode
Cathode/Anode
Emitter
Collector

Outline Dimensions

(Unit : mm)





Date code (2 digit)

			ì		
1st o	ligit		2nd digit		
Year of p	roduction		Month of production		
Mark	A.D	Mark	Month	Mark	
А	2002	Р	January	1	
В	2003	R	February	2	
С	2004	S	March	3	
D	2005	Т	April	4	
Е	2006	U	May	5	
F	2007	V	June	6	
Н	2008	W	July	7	
J	2009	Х	August	8	
K	2010	А	September	9	
L	2011	В	October	0	
М	2012	С	November	N	
Ν	:	:	December	D	
	Year of p Mark A B C D E F H J K J K L M	A 2002 B 2003 C 2004 D 2005 E 2006 F 2007 H 2008 J 2009 K 2010 L 2011 M 2012	Year of production Mark A.D Mark A 2002 P B 2003 R C 2004 S D 2005 T E 2006 U F 2007 V H 2008 W J 2009 X K 2010 A L 2011 B M 2012 C	Year of productionMonth ofMarkA.DMarkMonthA2002PJanuaryB2003RFebruaryC2004SMarchD2005TAprilE2006UMayF2007VJuneH2008WJulyJ2009XAugustK2010ASeptemberL2011BOctoberM2012CNovember	

repeats in a 20 year cycle

Factory identification mark

Factory identification Mark	Country of origin	
no mark	Japan	
	Indonesia	
$\overline{\nabla}$	Philippines	
	China	

* This factory making is for identification purpose only.

Please contact the local SHARP sales representative to see the actual status of the production.

Rank mark

Refer to the Model Line-up table

■ Absolute Maximum Ratings

	Absolute Maximum Ratings (T _a =25°C)							
	Parameter	Symbol	Rating	Unit				
ť	Forward current	I _F	±10	mA				
Input	*1 Peak forward current	I _{FM}	±200	mA				
I	Power dissipation	Р	15	mW				
	Collector-emitter voltage	V _{CEO}	*4 80	V				
Output	Emitter-collector voltage	V _{ECO}	6	V				
Out	Collector current	I _C	50	mA				
	Collector power dissipation	P _C	150	mW				
1	Fotal power dissipation	P _{tot}	170	mW				
*2 Isolation voltage		V _{iso (rms)}	5.0	kV				
Operating temperature		T _{opr}	-30 to +100	°C				
Storage temperature		T _{stg}	-55 to +125	°C				
*3 Soldering temperature		T _{sol}	260	°C				

*1 Pulse width≤100µs, Duty ratio : 0.001 *2 40 to 60%RH, AC for 1 minute, f=60Hz

*3 For 10s *4 Up to Date code "P8"(August 2002)VcE0:70V.

■ Electro-optical Characteristics

 $(T_a=25^{\circ}C)$

	•						(1 a =0 0)	
Parameter Symbol		Conditions	MIN.	TYP.	MAX.	Unit		
	Forward voltage		$V_{\rm F}$	I _F =±10mA	-	1.2	1.4	V
Input	Terminal capacitance		Ct	V=0, f=1kHz	-	30	250	pF
	Collector dark current		I _{CEO}	V_{CE} =50V, I_{F} =0	-	-	100	nA
	Collector-emitter breakdown voltage		BV _{CEO}	$I_{C}=0.1 \text{mA}, I_{F}=0$	*5 80	-	_	V
Output	Emitter-collector breakdown voltage		BV_{ECO}	$I_{E}=10\mu A, I_{F}=0$	6	-	-	V
	Collector current		I _C	$I_F=\pm 0.5 \text{mA}, V_{CE}=5 \text{V}$	0.25	-	2.0	mA
Transfer charac- teristics	Collector-emitter saturation voltage		V _{CE (sat)}	$I_F=\pm 10mA$, $I_C=1mA$	_	-	0.2	V
	Isolation resistance		R _{ISO}	DC500V, 40 to 60%RH	5×10 ¹⁰	1×10^{11}	-	Ω
	Floating capacitance		C_{f}	V=0, f=1MHz	-	0.6	1.0	pF
	Response time	Rise time	t _r	$V_{CE}=2V, I_{C}=2mA, R_{L}=100\Omega$	-	4	18	μs
		Fall time	$t_{\rm f}$		-	3	18	μs
	Common mode rejection voltage C		CMR	$\begin{array}{l} T_a\!\!=\!\!25^\circ\!C,R_L\!\!=\!\!470\Omega,V_{CM}\!\!=\!\!1.5kV(peak)\\ I_F\!\!=\!\!0,V_{CC}\!\!=\!\!9V,V_{np}\!\!=\!\!100mV \end{array}$	10	-	_	kV/µs

*5 Up to Date code "P8"(August 2002)BV $_{\rm CEO\geq}70V.$



■ Model Line-up

	•				
Lead Form	Through-Hole	SMT Gullwing		$I_C [mA]$ ($I_F=\pm 0.5mA$, $V_{CE}=5V$, $T_a=25^{\circ}C$)	
Daalaaga	Sle	eve	Rank mark		
Package	100pcs	/sleeve			
Model No.	PC81410NSZ	PC81410NIZ	with or without	0.25 to 2.0	
	PC81411NSZ	PC81411NIZ	А	0.5 to 1.5	

Please contact a local SHARP sales representative to inquire about production status and Lead-Free options.



Fig.1 Test Circuit for Common Mode Rejection Voltage

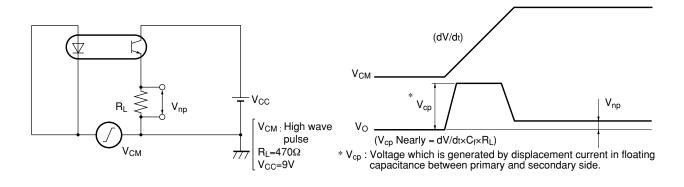


Fig.2 Forward Current vs. Ambient Temperature

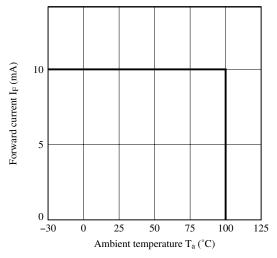


Fig.4 Collector Power Dissipation vs. Ambient Temperature

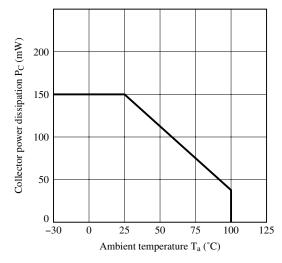
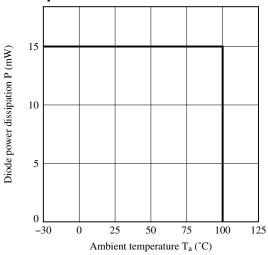


Fig.3 Diode Power Dissipation vs. Ambient Temperature





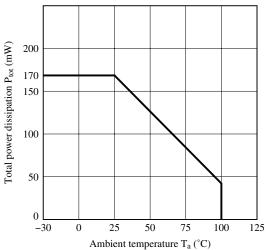
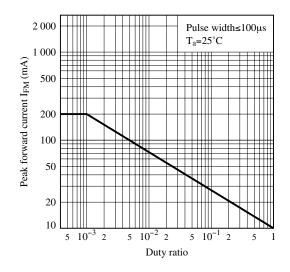
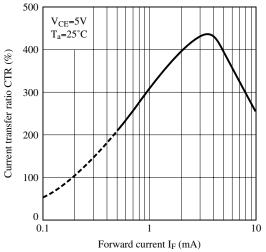


Fig.6 Peak Forward Current vs. Duty Ratio

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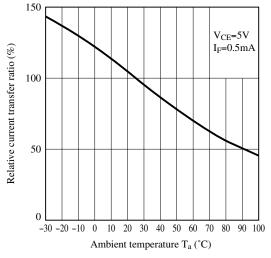


Fig.7 Forward Current vs. Forward Voltage

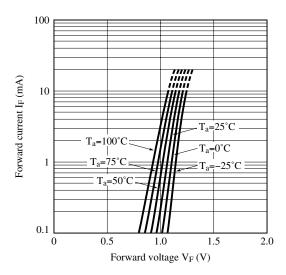


Fig.9 Collector Current vs. Collector-emitter Voltage

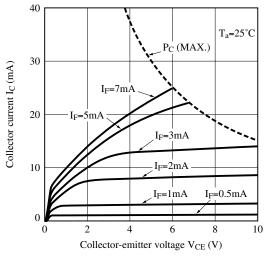


Fig.11 Collector - emitter Saturation Voltage vs. Ambient Temperature

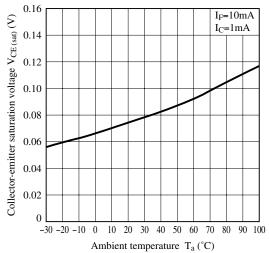
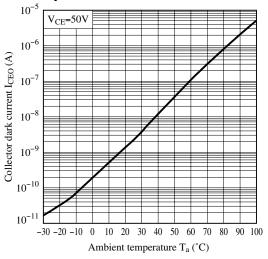
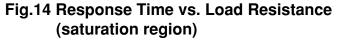
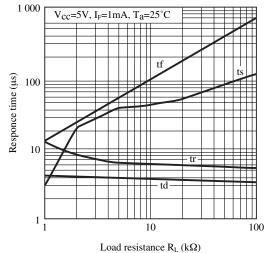




Fig.12 Collector Dark Current vs. Ambient Temperature









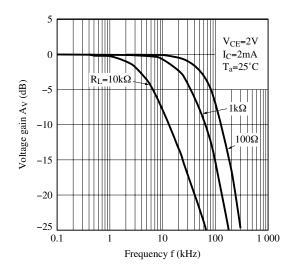


Fig.13 Response Time vs. Load Resistance (active region)

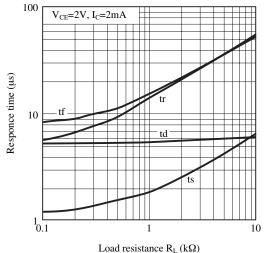
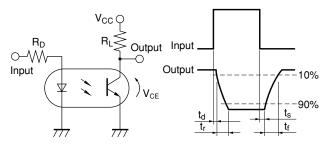
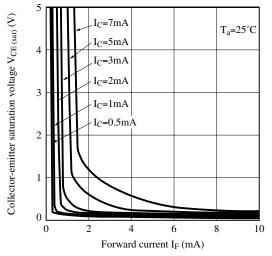


Fig.15 Test Circuit for Response Time



Please refer to the conditions in Fig.13 and Fig.14.





Remarks : Please be aware that all data in the graph are just for reference and not for guarantee.



Design Considerations

Design guide

While operating at I_{F} <0.5mA, CTR variation may increase. Please make design considering this fact.

In case that some sudden big noise caused by voltage variation is provided between primary and secondary terminals of photocoupler some current caused by it is floating capacitance may be generated and result in false operation since current may go through IRED or current may change.

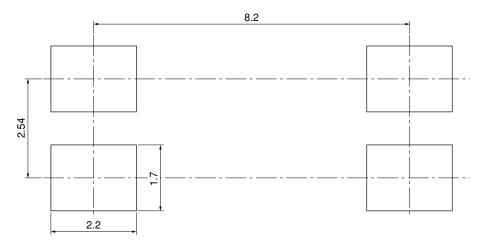
If the photocoupler may be used under the circumstances where noise will be generated we recommend to use the bypass capacitors at the both ends of IRED.

This product is not designed against irradiation and incorporates non-coherent IRED.

Degradation

In general, the emission of the IRED used in photocouplers will degrade over time. In the case of long term operation, please take the general IRED degradation (50% degradation over 5years) into the design consideration.

• Recommended Foot Print (reference)



☆ For additional design assistance, please review our corresponding Optoelectronic Application Notes.

(Unit : mm)

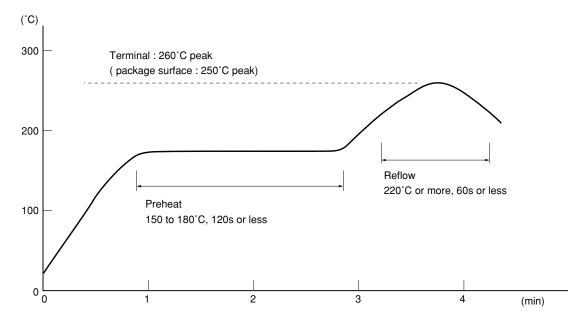


Manufacturing Guidelines

Soldering Method

Reflow Soldering:

Reflow soldering should follow the temperature profile shown below. Soldering should not exceed the curve of temperature profile and time. Please don't solder more than twice.



Flow Soldering :

Due to SHARP's double transfer mold construction submersion in flow solder bath is allowed under the below listed guidelines.

Flow soldering should be completed below 270°C and within 10s. Preheating is within the bounds of 100 to 150°C and 30 to 80s. Please don't solder more than twice.

Hand soldering

Hand soldering should be completed within 3s when the point of solder iron is below 400°C. Please don't solder more than twice.

Other notices

Please test the soldering method in actual condition and make sure the soldering works fine, since the impact on the junction between the device and PCB varies depending on the tooling and soldering conditions.



• Cleaning instructions

Solvent cleaning:

Solvent temperature should be 45°C or below Immersion time should be 3minutes or less

Ultrasonic cleaning:

The impact on the device varies depending on the size of the cleaning bath, ultrasonic output, cleaning time, size of PCB and mounting method of the device.

Therefore, please make sure the device withstands the ultrasonic cleaning in actual conditions in advance of mass production.

Recommended solvent materials:

Ethyl alcohol, Methyl alcohol and Isopropyl alcohol

In case the other type of solvent materials are intended to be used, please make sure they work fine in actual using conditions since some materials may erode the packaging resin.

• Presence of ODC

This product shall not contain the following materials.

And they are not used in the production process for this device.

Regulation substances:CFCs, Halon, Carbon tetrachloride, 1.1.1-Trichloroethane (Methylchloroform) Specific brominated flame retardants such as the PBBOs and PBBs are not used in this product at all.



Package specification

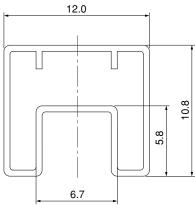
• Sleeve package

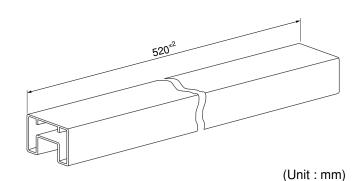
Package materials Sleeve : HIPS (with anti-static material) Stopper : Styrene-Elastomer

Package method

MAX. 100pcs of products shall be packaged in a sleeve.Both ends shall be closed by tabbed and tabless stoppers.The product shall be arranged in the sleeve with its primary side mark on the tabless stopper side.MAX. 20 sleeves in one case.

Sleeve outline dimensions





Sheet No.: D2-A03701EN

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- --- Personal computers
- --- Office automation equipment
- --- Telecommunication equipment [terminal]
- --- Test and measurement equipment
- --- Industrial control
- --- Audio visual equipment
- --- Consumer electronics

(ii) Measures such as fail-safe function and redundant design should be taken to ensure reliability and safety when SHARP devices are used for or in connection with equipment that requires higher reliability such as:

- --- Transportation control and safety equipment (i.e., aircraft, trains, automobiles, etc.)
- --- Traffic signals
- --- Gas leakage sensor breakers
- --- Alarm equipment
- --- Various safety devices, etc.

(iii) SHARP devices shall not be used for or in connection with equipment that requires an extremely high level of reliability and safety such as:

- --- Space applications
- --- Telecommunication equipment [trunk lines]
- --- Nuclear power control equipment
- --- Medical and other life support equipment (e.g., scuba).

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